

# PC8171xNSZ1B Series

# DIP 4pin High CMR, Low Input Current Photocoupler



## ■ Description

PC8171xNSZ1B Series contains an IRED optically coupled to a phototransistor. It is packaged in a 4-pin DIP. Input-output isolation voltage(rms) is 5kV. Collector-emitter voltage is 80V. CTR is 100% to 600% (at  $I_F$ =0.5mA, $V_{CE}$ =5V,Ta=25°C)

# ■ Agency approvals/Compliance

- 1. Recognized by UL1577 (Double protection isolation), file No. E64380 (as model No. **PC8171**)
- 2. Package resin: UL flammability grade (94V-0)

#### ■ Features

- 1. 4-pin DIP package
- 2. Double transfer mold package (Ideal for Flow Soldering)
- 3. Low input current type(I<sub>F</sub>=0.5mA)
- High noise immunity due to high common mode rejection voltage (CMR: MIN.10kV/µs)
- 5. High collector-emitter voltage(V<sub>CEO</sub>: 80V)
- 6. High isolation voltage between input and output (Viso(rms): 5kV)
- 7. RoHS directive compliant

# ■ Applications

Programmable controllers

- 1. Facsimiles
- 2. Telephones

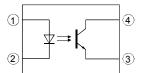
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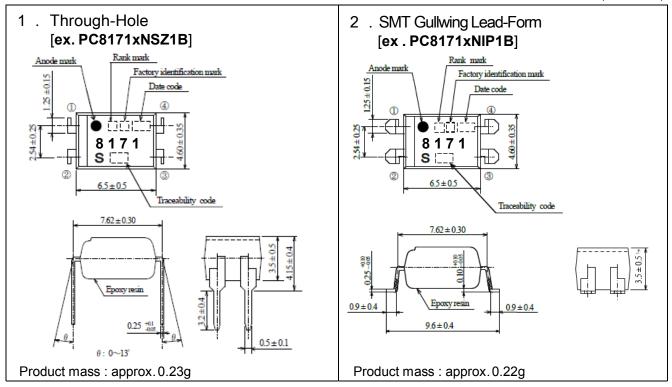


# ■ Internal Connection Diagram



- 1) Anode
- ② Cathode
- ③ Emitter
- (4) Collector

■ Outline (Unit:mm)





# Date code indication (Ex.)

3-digit number shall be marked the age indication of 1-digit number, and week code of 2-digit number. Week code "01" indicate the week including the first Thursday of January. And later, Monday is the starting point.

Year Week	Year	Week
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Date code	MON	TUE	WED	THU	FRI	SAT	SUN
652	12/26	12/27	12/28	12/29	12/30	12/31	1/1
701	1/2	1/3	1/4	1/5	1/6	1/7	1/8
702	1/9	1/10	1/11	1/12	1/13	1/14	1/15
703	1/16	1/17	1/18	1/19	1/20	1/21	1/22
	•	•	•	•	•	•	•
		•	•	-	-		
		•				•	•
752	12/11	12/12	12/13	12/14	12/15	12/16	12/17
751	12/18	12/19	12/20	12/21	12/22	12/23	12/24
752	12/25	12/26	12/27	12/28	12/29	12/30	12/31
801	1/1	1/2	1/3	1/4	1/5	1/6	1/7

# Factory identification mark and Plating material

Factory identification Mark	Country of origin	Plating material
K	Japan	SnBi (Bi : 1∼4%)

## Rank mark

Refer to the Model Line-up table.



# ■ Absolute maximum ratings

(Ta=25°C)

	Parameter		Rating	Unit
	Forward current	$I_F$	10	mA
T4	*1 Peak forward current	$I_{FM}$	200	mA
Input	Reverse voltage	$V_R$	6	V
	Power dissipation	P	15	mW
	Collector-emitter voltage	$V_{CEO}$	80	V
0	Emitter-collector voltage	V <sub>ECO</sub>	6	V
Output	Collector current	$I_{C}$	50	mA
	Collector power dissipation	P <sub>C</sub>	150	mW
Total 1	power dissipation	P <sub>tot</sub>	170	mW
*2 Isolati	*2 Isolation voltage		5	kV
Operating temperature		Topr	-30  to  +100	$^{\circ}$
Storage temperature		T <sub>stg</sub>	-55 to +125	$^{\circ}$
*2 Solder	ring temperature	$T_{sol}$	270	${\mathbb C}$

<sup>\*1</sup> Pulse width  $\leq 100 \mu s$ , Duty ratio: 0.001

# ■ Electro-optical Characteristics

(Ta=25°C)

	Parameter		Symbol	Condition	MIN.	TYP.	MAX.	Unit
	Forward voltage		$V_{\rm F}$	I <sub>F</sub> =5mA	_	1.2	1.4	V
Input	Reverse current		$I_R$	$V_R=4V$	_	_	10	μΑ
	Terminal capacitance		Ct	V=0, f=1kHz	_	30	250	pF
	Dark current		$I_{CEO}$	$V_{CE} = 50V, I_{F} = 0$	_	_	100	nA
Output	Collector-emitter breakdov	wn voltage	BV <sub>CEO</sub>	$I_{C}=0.1 \text{mA}, I_{F}=0$	80	_	_	V
	Emitter-collector breakdown voltage		BV <sub>ECO</sub>	$I_{E}=10\mu A, I_{F}=0$	6	_	_	V
	Collector current		$I_{C}$	$I_F=0.5mA, V_{CE}=5V$	0.5	_	3.0	mA
	Collector-emitter saturation voltage Ter Isolation resistance		V <sub>CE(sat)</sub>	I <sub>F</sub> =10mA, I <sub>C</sub> =1mA	_	-	0.2	V
Transfer			R <sub>ISO</sub>	DC500V, 40 to 60%RH	5×10 <sup>10</sup>	1×10 <sup>11</sup>	_	Ω
charac-	Floating capacitance		$C_{\mathrm{f}}$	V=0, f=1MHz	_	0.6	1.0	pF
teristics	Response time	Risetime	$t_{r}$	$V_{CE}$ =2 $V$ , $I_C$ =2 $mA$ , $R_L$ =100 $\Omega$	_	4	18	μs
		Falltime	$t_{\rm f}$		_	3	18	μs
	Common mode rejection ratio		CMR	$\begin{array}{c} Ta{=}25^{\circ}C, R_L{=}470\Omega \\ V_{CM}{=}1.5kV(peak), \\ I_F{=}0, Vcc{=}9V, Vnp{=}100mV \end{array}$	10	_	_	kV/μs

<sup>\*2</sup> AC for 1 min, 40 to 60%RH

<sup>\*3</sup> For 10 s



# ■ Model Line-up

Lead Form	Through-Hole		I <sub>C</sub> [mA]
	Sleeve	Rank mark	(I <sub>F</sub> =0.5mA,
Package	100pcs/sleeve		V <sub>CE</sub> =5V, T <sub>a</sub> =25°C)
- I ackage	·		<del></del>
	PC81710NSZ1B	with or "_"	0.5 ~ 3.0
	PC81711NSZ1B	A	0.6 ~ 1.5
Model No.	PC81712NSZ1B	В	0.8 ~ 2.0
	PC81713NSZ1B	С	1.0 ~ 2.5
	PC81716NSZ1B	<b>81716NSZ1B</b> B or C	
		•	•
Lead Form	SMT Gullwing		I <sub>C</sub> [mA]
	Taping	Rank mark	(I <sub>F</sub> =0.5mA,
5 .	2.000naa/raal	- Kankinaik	V <sub>CE</sub> =5V,
Package	2,000pcs/reel		T <sub>a</sub> =25°C)
	PC81710NIP1B	with or "_"	0.5 ~ 3.0
	PC81711NIP1B	A	0.6 ~ 1.5
Model No.	PC81712NIP1B	В	0.8 ~ 2.0
	PC81713NIP1B	С	1.0 ~ 2.5
	PC81716NIP1B	B or C	0.8 ~ 2.5

Please contact a local SHARP sales representative to inquire about production status.



Fig.1 Forward Current vs. Ambient Temperature

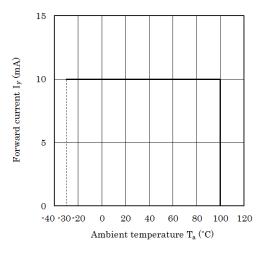


Fig.3 Collector Power Dissipation vs.
Ambient Temperature

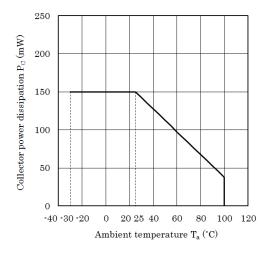


Fig.2 Diode Power Dissipation vs.
Ambient Temperature

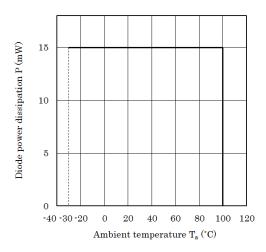


Fig.4 Total Power Dissipation vs. Ambient Temperature

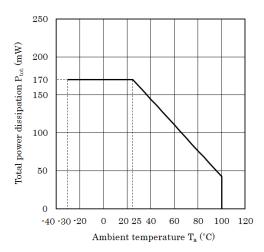
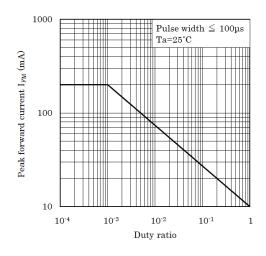


Fig.5 Peak Forward Current vs. Duty Ratio Fig.6 Forward Current vs. Forward Voltage



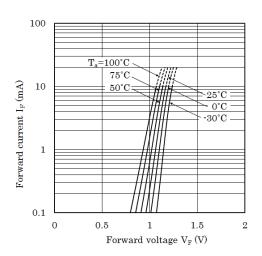




Fig.7 Current Transfer Ratio vs. Forward Current

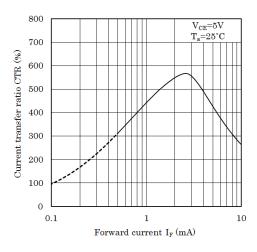


Fig.9 Relative Current Transfer Ratio vs.
Ambient Temperature

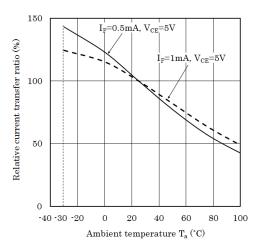


Fig.11 Collector Dark Current vs.

Ambient Temperature

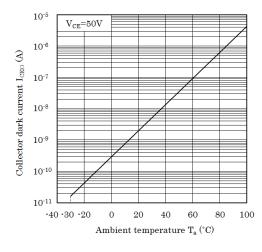


Fig.8 Collector Current vs.
Collector-emitter Voltage

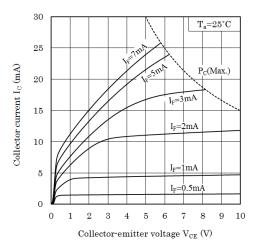


Fig.10 Collector - emitter Saturation Voltage vs. Ambient Temperature

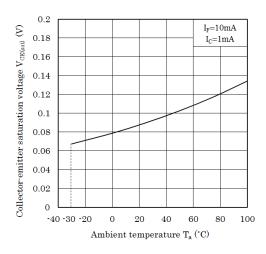


Fig.12 Collector-emitter Saturation Voltage vs. Forward Current

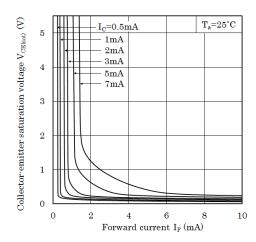




Fig.13 Response Time vs. Load Resistance

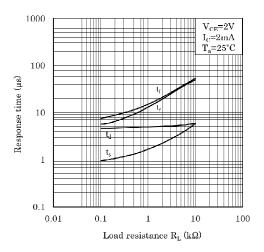


Fig.14 Test Circuit for Response Time

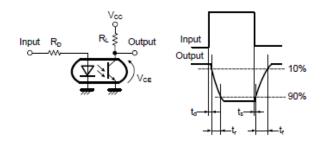


Fig.15 Frequency Response

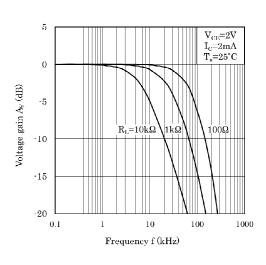


Fig.16 Test Circuit for Frequency Response

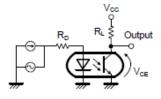
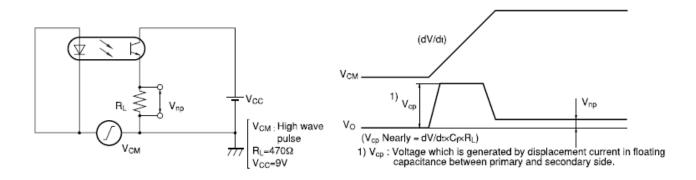


Fig.17 Test Circuit for Common Mode Rejection Voltage



Remarks: Please be aware that all data in the graph are just for reference and not for guarantee.



## ■ Design Considerations

## Design guide

While operating at  $I_F$ <0.5mA, CTR variation may increase. Please make design considering this fact.

In case that some sudden big noise caused by voltage variation is provided between primary and secondary terminals of photocoupler some current caused by it is floating capacitance may be generated and result in false operation since current may go through IRED or current may change.

If the photocoupler may be used under the circumstances where noise will be generated we recommend to use the bypass capacitors at the both ends of IRED.

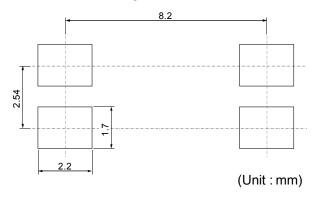
This product is not designed against irradiation and incorporates non-coherent IRED.

#### Degradation

In general, the emission of the IRED used in photocouplers will degrade over time. In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

### • Recommended foot print (reference)

SMT Gullwing lead-form





# ■ Manufacturing Guidelines

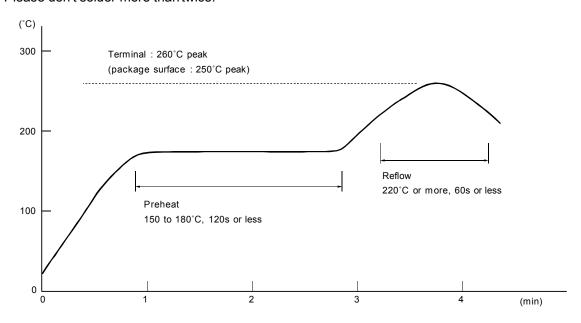
## Soldering Method

## Reflow Soldering:

Reflow soldering should follow the temperature profile shown below.

Soldering should not exceed the curve of temperature profile and time.

Please don't solder more than twice.



# Flow Soldering:

Due to SHARP's double transfer mold construction submersion in flow solder bath is allowed under the below listed guidelines.

Flow soldering should be completed below 270°C and within 10s.

Preheating is within the bounds of 100 to 150°C and 30 to 80s.

Please don't solder more than twice.

## Hand soldering

Hand soldering should be completed within 3s when the point of solder iron is below 400°C.

Please don't solder more than twice.

#### Other notice

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the tooling and soldering conditions.



# Cleaning instructions

#### Solvent cleaning:

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

#### Ultrasonic cleaning:

The impact on the device varies depending on the size of the cleaning bath, ultrasonic output, cleaning time, size of PCB and mounting method of the device.

Therefore, please make sure the device withstands the ultrasonic cleaning in actual conditions in advance of mass production.

#### Recommended solvent materials:

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

In case the other type of solvent materials are intended to be used, please make sure they work fine in actual using conditions since some materials may erode the packaging resin.

#### Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this product.

Regulation substances: CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBB and PBDE are not used in this product at all.

- The RoHS directive(2011/65/EU)
   This product complies with the RoHS directive(2011/65/EU)
   Object substances: mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls
   ( PBB ) and polybrominated diphenyl ethers ( PBDE )
- (2) Content of six substances specified in Management Methods for Control of Pollution Caused by Electronic Information Products Regulation (Chinese: 电子信息产品污染控制管理办法).

#### Marking Styles for the Names and Contents of the Hazardous Substances

			Haza	ardous Substances		
Category	Lead (Pb)	Mercury (Hg)	Cadmium (Cd)	Hexavalent chromium (Cr <sup>6+</sup> )	Polybrominated biphenyls (PBB)	Polybrominated diphenyl ethers (PBDE)
Photocoupler	0	0	0	0	0	0

This table is prepared in accordance with the provisions of SJ/T 11364.

• : Indicates that said hazardous substance contained in all of the homogeneous materials for this part is below the limit requirement of GB/T 26572.



# ■ Package specification

# • Sleeve package

# Through-Hole

# Package materials

Sleeve: HIPS/PS or PC (with anti-static material)

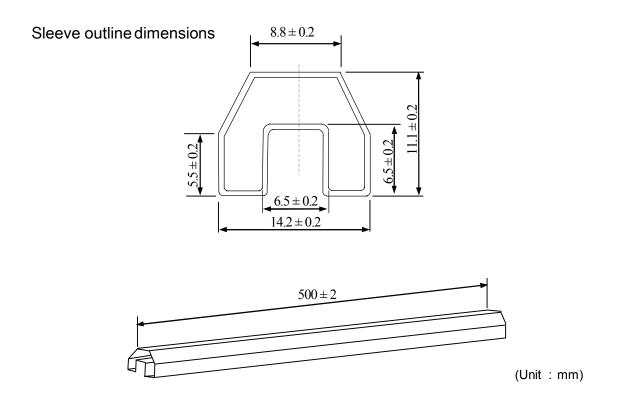
Stopper: EPM

## Package method

MAX. 100pcs. of products shall be packaged in a sleeve and both of sleeve edges shall be fixed by stoppers.

MAX. 25 sleeves (Product: 2,500pcs.) above shall be packaged in inner case and sealed by tape.

Max 2 bags(product: 5,000pcs) above shall be packaged in packing case, and put a cushioning material inside.





# • Tape and Reel package

# **SMT Gullwing**

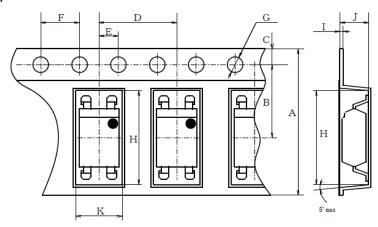
# Package materials

Carrier tape: PS

Cover tape: PET (three layer system)

Reel: PS

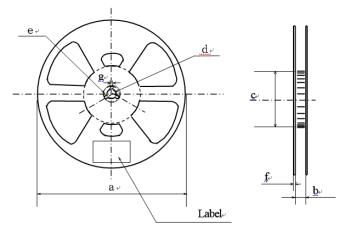
# Carrier tape structure and Dimensions



Dimensions List (Unit: mm)

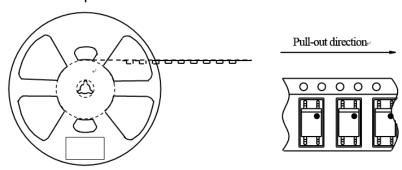
A	В	С	D	Е	F	G
16.0±0.3	7.5 <sup>±0.1</sup>	1.75 <sup>±0.10</sup>	8.0 <sup>±0.1</sup>	2.0 <sup>±0.1</sup>	$4.0^{\pm0.1}$	$\phi 1.5^{+0.1}_{-0.0}$
Н	I	J	K			
10.3±0.1	$0.40^{\pm0.05}$	4.0 <sup>±0.1</sup>	5.3 <sup>±0.1</sup>			

## Reel structure and Dimensions



Dimensio	ns List	(U	nit : mm)
a	b	c	d
ф330	17.5 <sup>±1.5</sup>	φ100 <sup>±1</sup>	φ13.0 <sup>±0.5</sup>
e	f	g	
φ21.0 <sup>±1</sup>	2.0 <sup>±0.5</sup>	2.0 <sup>±0.5</sup>	

# Direction of product insertion



[Packing: 2,000pcs/reel]



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  - --- Telecommunication equipment [terminal]
  - --- Test and measurement equipment
  - --- Industrial control
  - --- Audio visual equipment
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- (ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection

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  - --- Traffic signals
  - --- Gas leakage sensor breakers
  - --- Alarm equipment
  - --- Various safety devices, etc.
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